

Description

The DMNH6012SPS-13 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = 60V I_{D} = 65A$

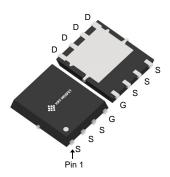
 $R_{DS(ON)} < 11 m\Omega V_{GS} = 10 V$

Application

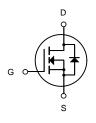
Battery protection

Load switch

Uninterruptible power supply



DFN5X6-8L



N-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
DMNH6012SPS-13	DFN5X6-8L	HXY MOSFET	5000

Absolute Maximum Ratings (Tc=25°C unless otherwise noted)

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	60	V
Vgs	Gate-Source Voltage	±20	V
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V	65	А
I _D @T _C =70°C	Continuous Drain Current, V _{GS} @ 10V	49	А
Ідм	Pulsed Drain Current ²	Pulsed Drain Current ² 180	
EAS	Single Pulse Avalanche Energy ³	Single Pulse Avalanche Energy ³ 56	
P _D @T _C =25°C	Total Power Dissipation ⁴	89	W
Тѕтс	Storage Temperature Range	Storage Temperature Range -55 to 150	
TJ	Operating Junction Temperature Range	erating Junction Temperature Range -55 to 150	
Reja	Thermal Resistance Junction-Ambient ¹ 62		°C/W



Electrical Characteristics (T_J=25°C unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units	
Off Charac	cteristic		I				
V _{(BR)DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250µA	60	-	-	V	
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =60V, V _{GS} =0V,	-	-	1.0	μA	
I _{GSS}	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} = ±20V	-	-	±100	nA	
On Charac	cteristics						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	1.0	1.6	2.5	V	
	Static Drain-Source on-Resistance	V _{GS} =10V, I _D =20A	-	8	11		
$R_{DS(on)}$		V _{GS} =4.5V, I _D =10A	- 14 20		20	mΩ	
Dynamic (Characteristics						
C _{iss}	Input Capacitance	\\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	-	930	-	pF	
Coss	Output Capacitance	V _{DS} =25V, V _{GS} =0V,	-	370	-	pF	
Crss	Reverse Transfer Capacitance	f=1.0MHz	-	20	-	pF	
Qg	Total Gate Charge		-	19	-	nC	
Q _{gs}	Gate-Source Charge	V_{DS} =30V, I_{D} =20A, V_{GS} =10V	-	4.8	-	nC	
Q_{gd}	Gate-Drain("Miller") Charge	VGS-10V	-	4.5	-	nC	
Switching	Characteristics						
t _{d(on)}	Turn-on Delay Time		_	4.9	-	ns	
t _r	Turn-on Rise Time	V _{DD} =30V, I _D =20A,	-	31	-	ns	
$t_{d(off)}$	Turn-off Delay Time	$R_G\text{=}1.6\Omega,V_{GS}\text{=}10V$	-	23	-	ns	
t _f	Turn-off Fall Time		-	8.7	-	ns	
Drain-Sou	rce Diode Characteristics and Maximi	um Ratings					
Is	Maximum Continuous Drain to Source Diode Forward Current		-	-	65	А	
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current			-	240	Α	
V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} =0V, I _S =30A	-	-	1.4	V	
t _{rr}	Body Diode Reverse Recovery Time	T -05°C	-	34	-	ns	
Q _{rr}	Body Diode Reverse Recovery Charge	T _J =25°C, I _F =20A,dI/dt=100A/μs	-	14	-	nC	

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

- 2. EAS condition: T_J =25°C, V_{DD} =30V, V_G =10V, R_G =25 Ω , L=0.5mH, I_{AS} =12A
- 3. Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%



Typical Performance Characteristics

Figure1: Output Characteristics

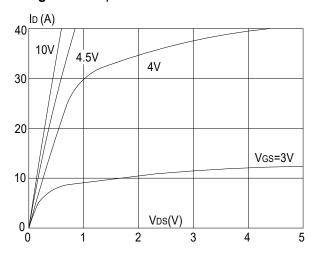


Figure 3:On-resistance vs. Drain Current

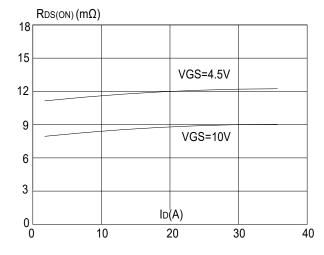


Figure 5: Gate Charge Characteristics

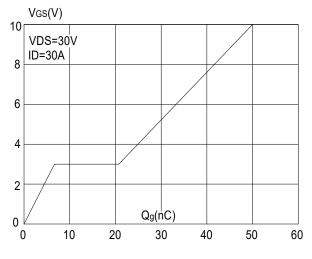


Figure 2: Typical Transfer Characteristics

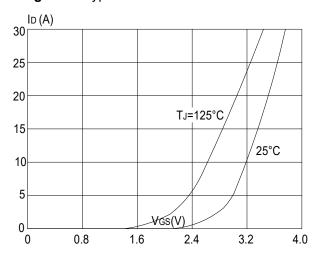


Figure 4: Body Diode Characteristics

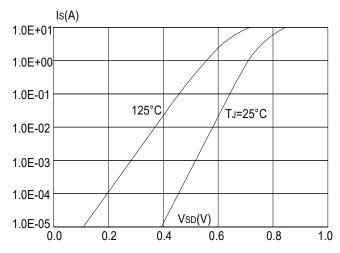


Figure 6: Capacitance Characteristics

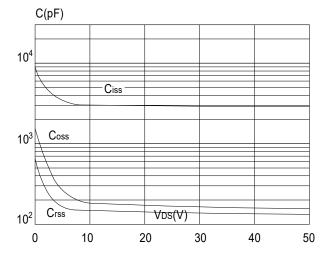




Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

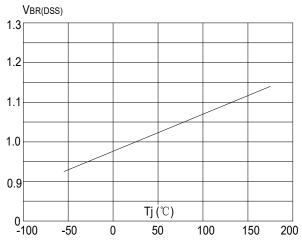


Figure 9: Maximum Safe Operating Area

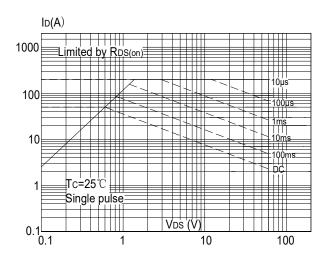


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case

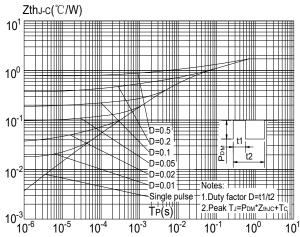


Figure 8: Normalized on Resistance vs. Junction Temperature

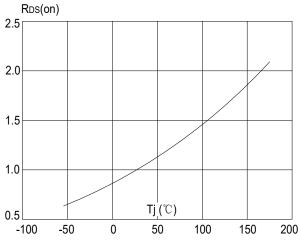
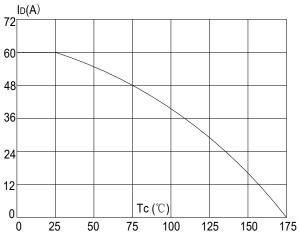
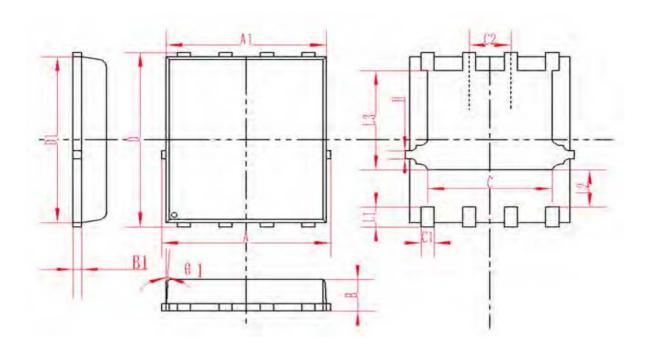


Figure 10: Maximum Continuous Drain Current vs. Case Temperature





DFN5X6-8L Package Information



SYMBOL	MM		INCH			
	MIN	NOM	MAX	MIN	NOM	MAX
А	4.95	5	5.05	0.195	0.197	0.199
A1	4.82	4.9	4.98	0.190	0.193	0.196
D	5.98	6	6.02	0.235	0.236	0.237
D1	5.67	5.75	5.83	0.223	0.226	0.230
В	0.9	0.95	1	0.035	0.037	0.039
B1	0.254REF		0.010REF			
С	3.95	4	4.05	0.156	0.157	0.159
C1	0.35	0.4	0.45	0.014	0.016	0.018
C2		1.27TYP			0.5TYP	
θ1	8°	10°	12°	8°	10°	12°
L1	0.63	0.64	0.65	0.025	0.025	0.026
L2	1.2	1.3	1.4	0.047	0.051	0.055
L3	3.415	3.42	3.425	0.134	0.135	0.135
Н	0.24	0.25	0.26	0.009	0.010	0.010

N-Channel Enhancement Mode MOSFET

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